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Collana	Image Processing, Computer Vision, Pattern Recognition, and Graphics ; ; 10597
Disciplina	006.4
Soggetti	Special purpose computers Artificial intelligence Natural language processing (Computer science) Optical data processing Biometrics (Biology) Special Purpose and Application-Based Systems Artificial Intelligence Natural Language Processing (NLP) Image Processing and Computer Vision Biometrics
Lingua di pubblicazione	Inglese
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Note generali	Includes Index.
Nota di contenuto	Pattern recognition and machine learning Signal and image processing Computer vision and video processing Soft and natural computing Speech and natural language processing Bioinformatics and computational biology Data mining and big data analytics Deep learning Spatial data science and engineering Applications of pattern recognition and machine intelligence.
Sommario/riassunto	This book constitutes the proceedings of the 7th International Conference on Pattern Recognition and Machine Intelligence, PReMI 2017,held in Kolkata, India, in December 2017. The total of 86 full papers presented in this volume were carefully reviewed

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and selected from 293 submissions. They were organized in topical sections named: pattern recognition and machine learning; signal and image processing; computer vision and video processing; soft and natural computing; speech and natural language processing; bioinformatics and computational biology; data mining and big data analytics; deep learning; spatial data science and engineering; and applications of pattern recognition and machine intelligence.